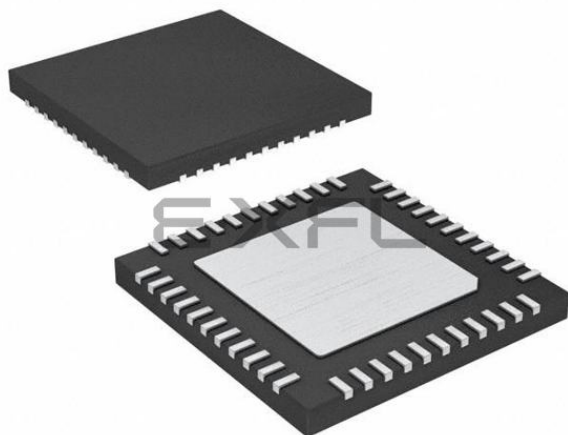




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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I ² C, IrDA, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	34
Program Memory Size	16KB (8K x 16)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	44-VFQFN Exposed Pad
Supplier Device Package	44-VQFN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega16c4-mh

4. Resources

A comprehensive set of development tools, application notes and datasheets are available for download on <http://www.atmel.com/avr>.

4.1 Recommended Reading

- Atmel AVR XMEGA C manual
- XMEGA application notes

This device data sheet only contains part specific information with a short description of each peripheral and module. The XMEGA C manual describes the modules and peripherals in depth. The XMEGA application notes contain example code and show applied use of the modules and peripherals.

All documentation are available from www.atmel.com/avr.

5. Capacitive Touch Sensing

The Atmel QTouch library provides a simple to use solution to realize touch sensitive interfaces on most Atmel AVR microcontrollers. The patented charge-transfer signal acquisition offers robust sensing and includes fully debounced reporting of touch keys and includes Adjacent Key Suppression™ (AKS™) technology for unambiguous detection of key events. The QTouch library includes support for the QTouch and QMatrix acquisition methods.

Touch sensing can be added to any application by linking the appropriate Atmel QTouch library for the AVR microcontroller. This is done by using a simple set of APIs to define the touch channels and sensors, and then calling the touch sensing API's to retrieve the channel information and determine the touch sensor states.

The QTouch library is FREE and downloadable from the Atmel website at the following location:

<http://www.atmel.com/tools/qtouchlibrary> For implementation details and other information, refer to the QTouch library user guide - also available for download from the Atmel website.

6. AVR CPU

6.1 Features

- 8/16-bit, high-performance Atmel AVR RISC CPU
 - 142 instructions
 - Hardware multiplier
- 32x8-bit registers directly connected to the ALU
- Stack in RAM
- Stack pointer accessible in I/O memory space
- Direct addressing of up to 16MB of program memory and 16MB of data memory
- True 16/24-bit access to 16/24-bit I/O registers
- Efficient support for 8-, 16-, and 32-bit arithmetic
- Configuration change protection of system-critical features

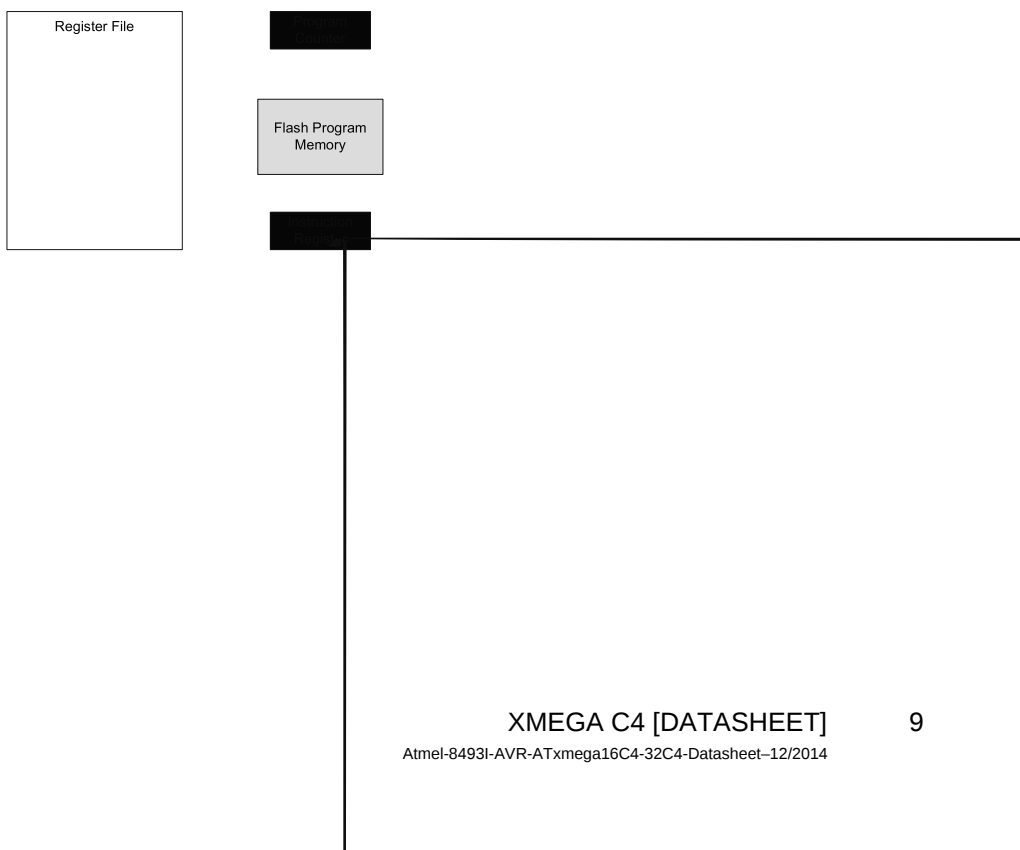
6.2 Overview

All Atmel AVR XMEGA devices use the 8/16-bit AVR CPU. The main function of the CPU is to execute the code and perform all calculations. The CPU is able to access memories, perform calculations, control peripherals, and execute the program in the flash memory. Interrupt handling is described in a separate section, refer to “Interrupts and Programmable Multilevel Interrupt Controller” on page 27.

6.3 Architectural Overview

In order to maximize performance and parallelism, the AVR CPU uses a Harvard architecture with separate memories and buses for program and data. Instructions in the program memory are executed with single-level pipelining. While one instruction is being executed, the next instruction is pre-fetched from the program memory. This enables instructions to be executed on every clock cycle. For details of all AVR instructions, refer to <http://www.atmel.com/avr>.

Figure 6-1. Block Diagram of the AVR CPU Architecture



Multipacket transfer enables a data payload exceeding the maximum packet size of an endpoint to be transferred as multiple packets without software intervention. This reduces the CPU intervention and the interrupts needed for USB transfers.

For low-power operation, the USB module can put the microcontroller into any sleep mode when the USB bus is idle and a suspend condition is given. Upon bus resumes, the USB module can wake up the microcontroller from any sleep mode.

PORTD has one USB. Notation of this is USB.

33. Electrical Characteristics

All typical values are measured at $T = 25^{\circ}\text{C}$ unless other temperature condition is given. All minimum and maximum values are valid across operating temperature and voltage unless other conditions are given.

33.1 Atmel ATxmega16C4

33.1.1 Absolute Maximum Ratings

Stresses beyond those listed in Table 33-1 under may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 33-1. Absolute Maximum Ratings

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{CC}	Power supply voltage		-0.3		4	V
I_{VCC}	Current into a V_{CC} pin				200	mA
I_{GND}	Current out of a GND pin				200	
V_{PIN}	Pin voltage with respect to GND and V_{CC}		-0.5		$V_{CC}+0.5$	V
I_{PIN}	I/O pin sink/source current		-25		25	mA
T_A	Storage temperature		-65		150	$^{\circ}\text{C}$
T_J	Junction temperature				150	

33.1.2 General Operating Ratings

The device must operate within the ratings listed in Table 33-2 in order for all other electrical characteristics and typical characteristics of the device to be valid.

Table 33-2. General Operating Conditions

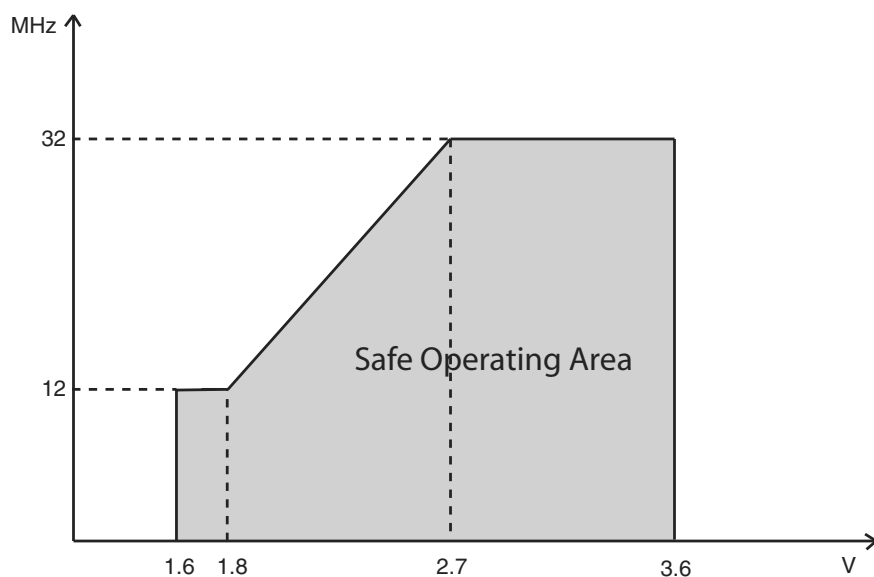
Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{CC}	Power supply voltage		1.60		3.6	V
AV_{CC}	Analog supply voltage		1.60		3.6	
T_A	Temperature range		-40		85	$^{\circ}\text{C}$
T_J	Junction temperature		-40		105	

Table 33-3. Operating Voltage and Frequency

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Clk_{CPU}	CPU clock frequency	$V_{CC} = 1.6\text{V}$	0		12	MHz
		$V_{CC} = 1.8\text{V}$	0		12	
		$V_{CC} = 2.7\text{V}$	0		32	
		$V_{CC} = 3.6\text{V}$	0		32	

The maximum CPU clock frequency depends on V_{CC} . As shown in Figure 33-1 the Frequency vs. V_{CC} curve is linear between $1.8V < V_{CC} < 2.7V$.

Figure 33-1. Maximum Frequency vs. V_{CC}



33.1.8 Bandgap and Internal 1.0V Reference Characteristics

Table 33-13. Bandgap and Internal 1.0V Reference Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Startup time	As reference for ADC	1 Clk _{PER} + 2.5μs			μs
		As input voltage to ADC and AC		1.5		
	Bandgap voltage			1.1		V
INT1V	Internal 1.00V reference	T = 85°C, after calibration	0.98	1	1.02	
	Variation over voltage and temperature	Calibrated at T = 85°C, V _{CC} = 3.0V		±1.0		%

33.1.9 Brownout Detection Characteristics

Table 33-14. Brownout Detection Characteristics⁽¹⁾

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V _{BOT}	BOD level 0 falling V _{CC}		1.50	1.62	1.75	V
	BOD level 1 falling V _{CC}			1.8		
	BOD level 2 falling V _{CC}			2.0		
	BOD level 3 falling V _{CC}			2.2		
	BOD level 4 falling V _{CC}			2.4		
	BOD level 5 falling V _{CC}			2.6		
	BOD level 6 falling V _{CC}			2.8		
	BOD level 7 falling V _{CC}			3.0		
t _{BOD}	Detection time	Continuous mode		0.4		μs
		Sampled mode		1000		
V _{HYST}	Hysteresis			1.2		%

Note: 1. BOD is calibrated at 85°C within BOD level 0 values, and BOD level 0 is the default level.

33.1.10 External Reset Characteristics

Table 33-15. External Reset Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t _{EXT}	Minimum reset pulse width		1000	90		ns
V _{RST}	Reset threshold voltage (V _{IH})	V _{CC} = 2.7 - 3.6V	0.6*V _{CC}			V
		V _{CC} = 1.6 - 2.7V	0.6*V _{CC}			
	Reset threshold voltage (V _{IL})	V _{CC} = 2.7 - 3.6V			0.5*V _{CC}	
		V _{CC} = 1.6 - 2.7V			0.4*V _{CC}	
R _{RST}	Reset pin pull-up resistor			25		kΩ

33.1.11 Power-on Reset Characteristics

Table 33-16. Power-on Reset Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$V_{POT-}^{(1)}$	POR threshold voltage falling V_{CC}	V_{CC} falls faster than 1V/ms	0.4	1.0		V
		V_{CC} falls at 1V/ms or slower	0.8	1.0		
V_{POT+}	POR threshold voltage rising V_{CC}			1.3	1.59	

Note: 1. V_{POT-} values are only valid when BOD is disabled. When BOD is enabled $V_{POT-} = V_{POT+}$.

33.1.12 Flash and EEPROM Memory Characteristics

Table 33-17. Endurance and Data Retention

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Flash	Write/Erase cycles	25°C	10K		Cycle
			85°C	10K		
			105°C	2K		
		Data retention	25°C	100		Year
			85°C	25		
			105°C	10		
	EEPROM	Write/Erase cycles	25°C	100K		Cycle
			85°C	100K		
			105°C	30K		
		Data retention	25°C	100		Year
			85°C	25		
			105°C	10		

Table 33-18. Programming Time

Symbol	Parameter	Condition	Min.	Typ. ⁽¹⁾	Max.	Units
	Chip erase ⁽²⁾	16KB Flash, EEPROM		45		ms
	Flash	Page erase		4		
		Page write		4		
		Atomic page erase and write		8		
	EEPROM	Page erase		4		
		Page write		4		
		Atomic page erase and write		8		

Notes: 1. Programming is timed from the 2MHz internal oscillator.
2. EEPROM is not erased if the EESAVE fuse is programmed.

Table 33-34. Current Consumption for Modules and Peripherals

Symbol	Parameter	Condition ⁽¹⁾	Min.	Typ.	Max.	Units
I _{CC}	ULP oscillator			0.8		μA
	32.768kHz int. oscillator			29		
	2MHz int. oscillator			85		
		DFLL enabled with 32.768kHz int. osc. as reference		115		
	32MHz int. oscillator			245		
		DFLL enabled with 32.768kHz int. osc. as reference		410		
	PLL	20x multiplication factor, 32MHz int. osc. DIV4 as reference		290		
	Watchdog timer			1.0		
	BOD	Continuous mode		138		
		Sampled mode, includes ULP oscillator		1.2		
	Internal 1.0V reference			175		mA
	Temperature sensor			170		
	ADC	16ksps V _{REF} = Ext. ref.		1.2		
			CURRLIMIT = LOW	1.0		
			CURRLIMIT = MEDIUM	0.9		
			CURRLIMIT = HIGH	0.8		
		75ksps V _{REF} = Ext. ref.	CURRLIMIT = LOW	1.7		
		300ksps V _{REF} = Ext. ref.		3.1		
	USART	Rx and Tx enabled, 9600 BAUD		11		μA
	Flash memory and EEPROM programming			4		mA

Note: 1. All parameters measured as the difference in current consumption between module enabled and disabled. All data at V_{CC} = 3.0V, Clk_{SYS} = 1MHz external clock without prescaling, T = 25°C unless other conditions are given.

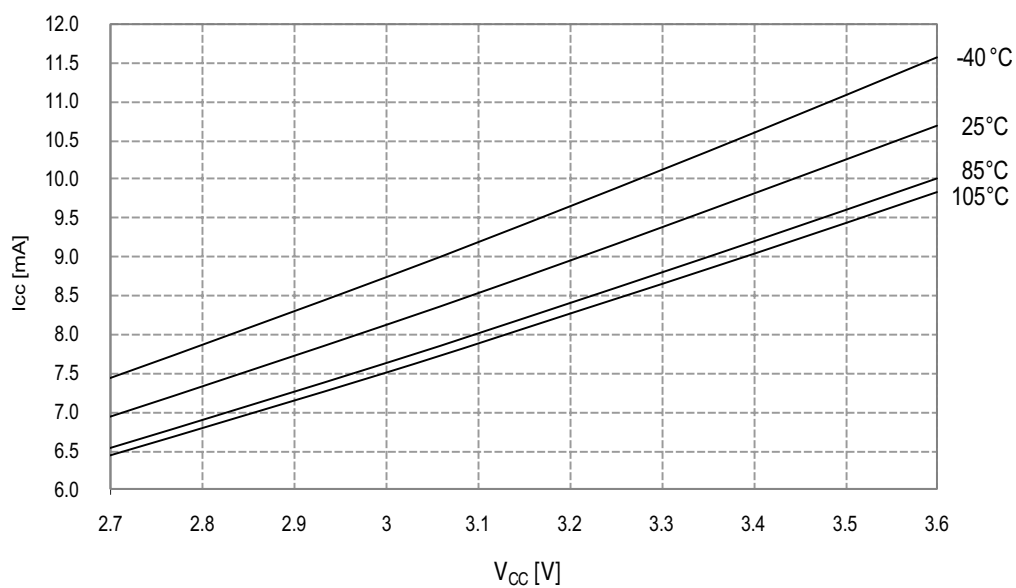
Table 33-58. Two-wire Interface Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{IH}	Input high voltage		$0.7 \cdot V_{CC}$		$V_{CC} + 0.5$	V
V_{IL}	Input low voltage		-0.5		$0.3 \cdot V_{CC}$	
V_{hys}	Hysteresis of Schmitt trigger inputs		$0.05 \cdot V_{CC}^{(1)}$			
V_{OL}	Output low voltage	3mA, sink current	0		0.4	
t_r	Rise time for both SDA and SCL		$20 + 0.1 C_b^{(1)(2)}$		300	ns
t_{of}	Output fall time from V_{IHmin} to V_{ILmax}	$10pF < C_b < 400pF^{(2)}$	$20 + 0.1 C_b^{(1)(2)}$		250	
t_{SP}	Spikes suppressed by input filter		0		50	
I_I	Input current for each I/O Pin	$0.1V_{CC} < V_I < 0.9V_{CC}$	-10		10	μA
C_I	Capacitance for each I/O Pin				10	pF
f_{SCL}	SCL clock frequency	$f_{PER}^{(3)} > \max(10f_{SCL}, 250kHz)$	0		400	kHz
R_P	Value of pull-up resistor	$f_{SCL} \leq 100kHz$	$\frac{V_{CC} - 0.4V}{3mA}$		$\frac{100ns}{C_b}$	Ω
		$f_{SCL} > 100kHz$			$\frac{300ns}{C_b}$	
$t_{HD;STA}$	Hold time (repeated) START condition	$f_{SCL} \leq 100kHz$	4.0			μs
		$f_{SCL} > 100kHz$	0.6			
t_{LOW}	Low period of SCL clock	$f_{SCL} \leq 100kHz$	4.7			
		$f_{SCL} > 100kHz$	1.3			
t_{HIGH}	High period of SCL clock	$f_{SCL} \leq 100kHz$	4.0			
		$f_{SCL} > 100kHz$	0.6			
$t_{SU;STA}$	Set-up time for a repeated START condition	$f_{SCL} \leq 100kHz$	4.7			
		$f_{SCL} > 100kHz$	0.6			
$t_{HD;DAT}$	Data hold time	$f_{SCL} \leq 100kHz$	0		3.45	
		$f_{SCL} > 100kHz$	0		0.9	
$t_{SU;DAT}$	Data setup time	$f_{SCL} \leq 100kHz$	250			
		$f_{SCL} > 100kHz$	100			
$t_{SU;STO}$	Setup time for STOP condition	$f_{SCL} \leq 100kHz$	4.0			
		$f_{SCL} > 100kHz$	0.6			
t_{BUF}	Bus free time between a STOP and START condition	$f_{SCL} \leq 100kHz$	4.7			
		$f_{SCL} > 100kHz$	1.3			

- Notes:
1. Required only for $f_{SCL} > 100kHz$.
 2. C_b = Capacitance of one bus line in pF.
 3. f_{PER} = Peripheral clock frequency.

Figure 34-7. Active Mode Supply Current vs. V_{CC}

$f_{SYS} = 32\text{MHz}$ internal oscillator



34.1.1.2 Idle Mode Supply Current

Figure 34-8. Idle Mode Supply Current vs. Frequency

$f_{SYS} = 0 - 1\text{MHz}$ external clock, $T = 25^\circ\text{C}$

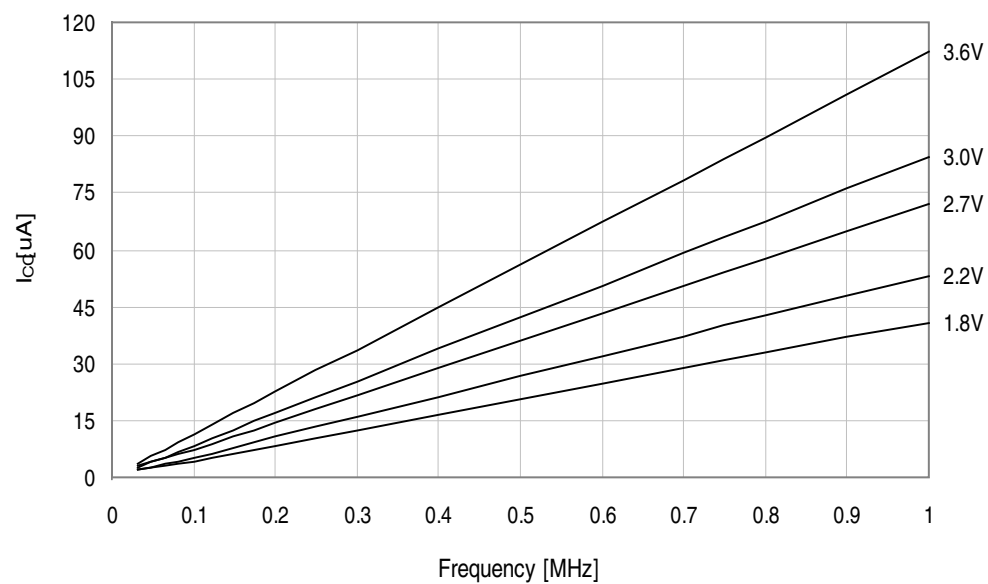
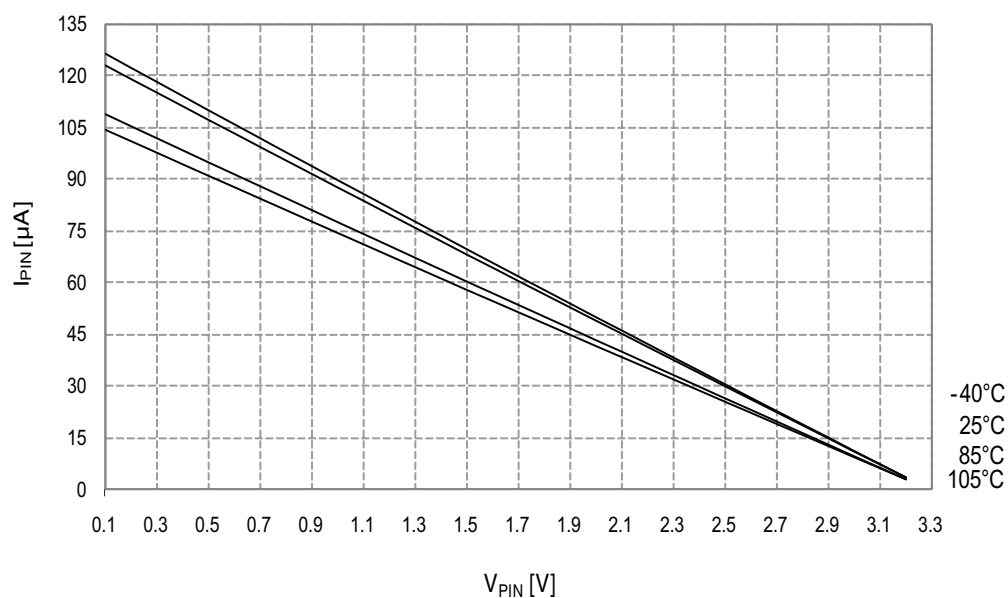


Figure 34-23. I/O Pin Pull-up Resistor Current vs. Input Voltage

$V_{CC} = 3.3V$



34.1.2.2 Output Voltage vs. Sink/Source Current

Figure 34-24. I/O Pin Output Voltage vs. Source Current

$V_{CC} = 1.8V$

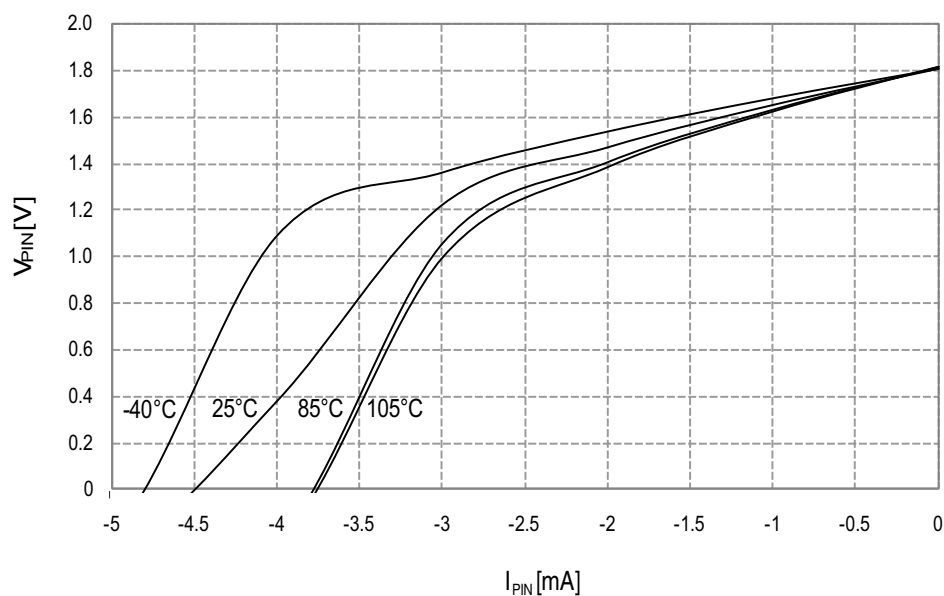
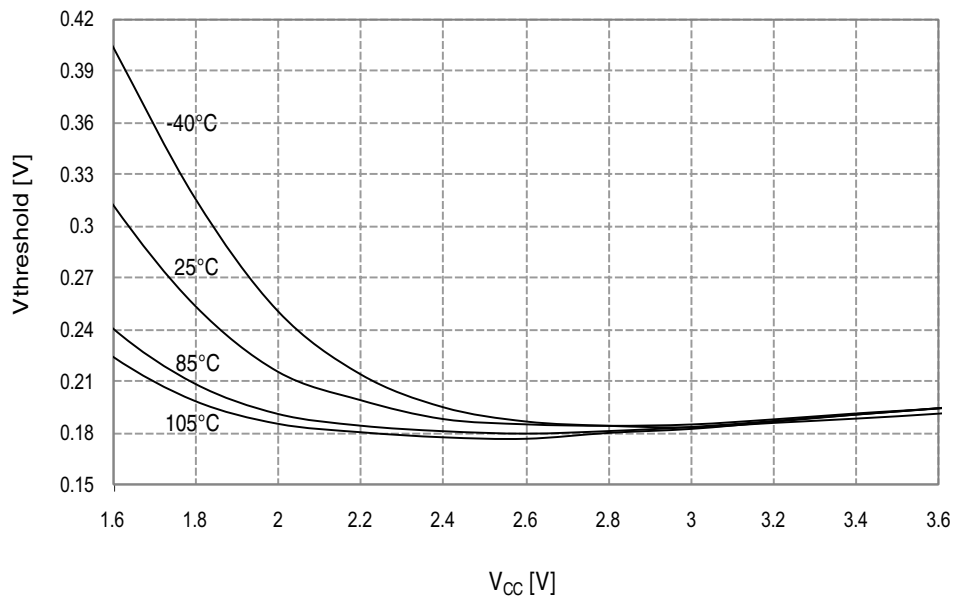


Figure 34-35. I/O Pin Input Hysteresis vs. V_{CC}



34.1.3 ADC Characteristics

Figure 34-36. INL Error vs. External V_{REF}
 $T = 25^\circ\text{C}$, $V_{CC} = 3.6\text{V}$, external reference

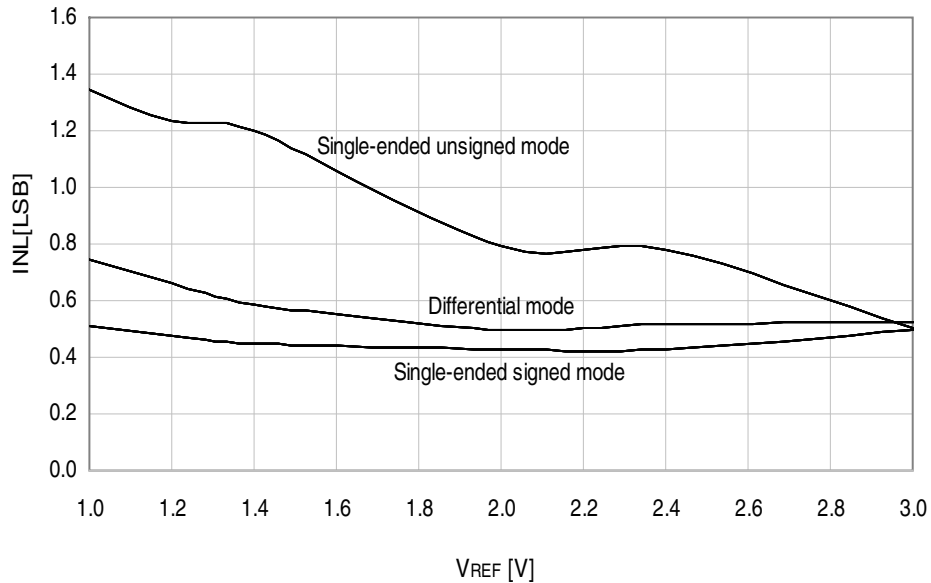


Figure 34-41.DNL Error vs. Input Code

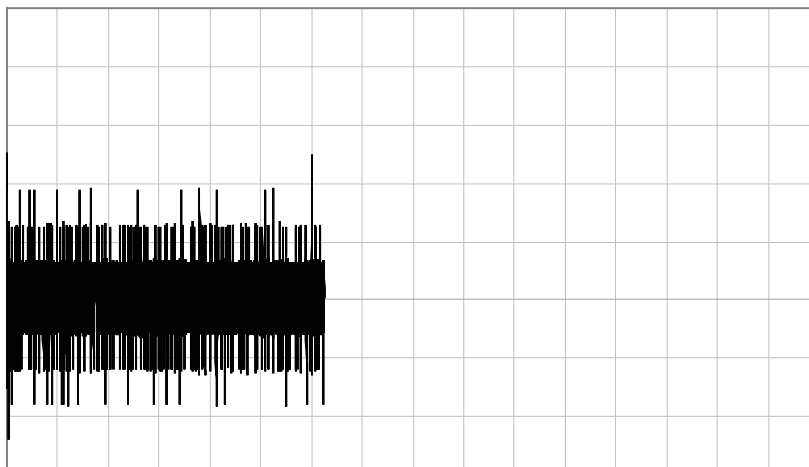


Figure 34-42. Gain Error vs. V_{REF}

$T = 25^{\circ}\text{C}$, $V_{CC} = 3.6\text{V}$, ADC sample rate = 300ksps

Figure 34-61. Reset Pin Input Threshold Voltage vs. V_{CC}

V_{IH} - Reset pin read as "1"

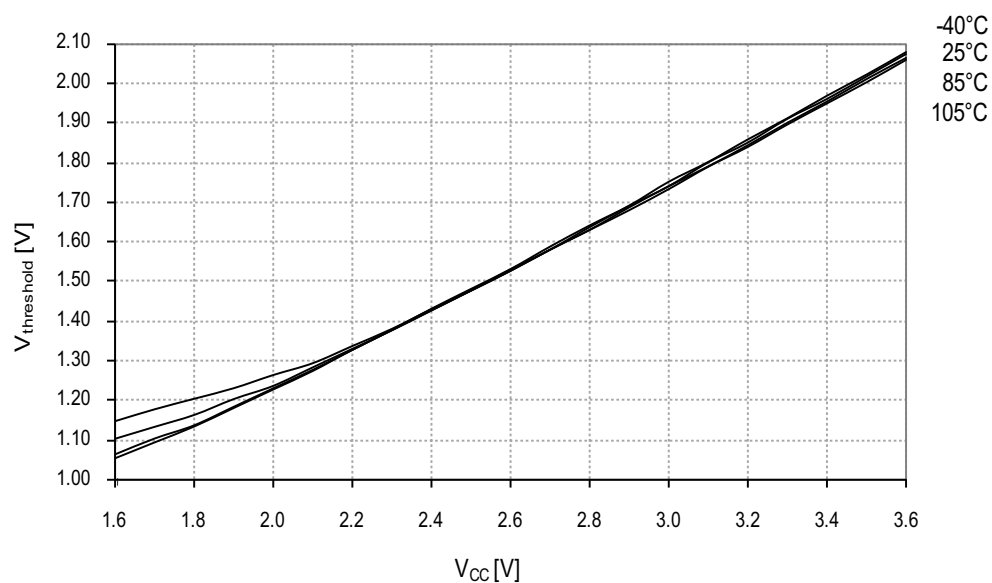


Figure 34-62. Reset Pin Input Threshold Voltage vs. V_{CC}

V_{IL} - Reset pin read as "0"

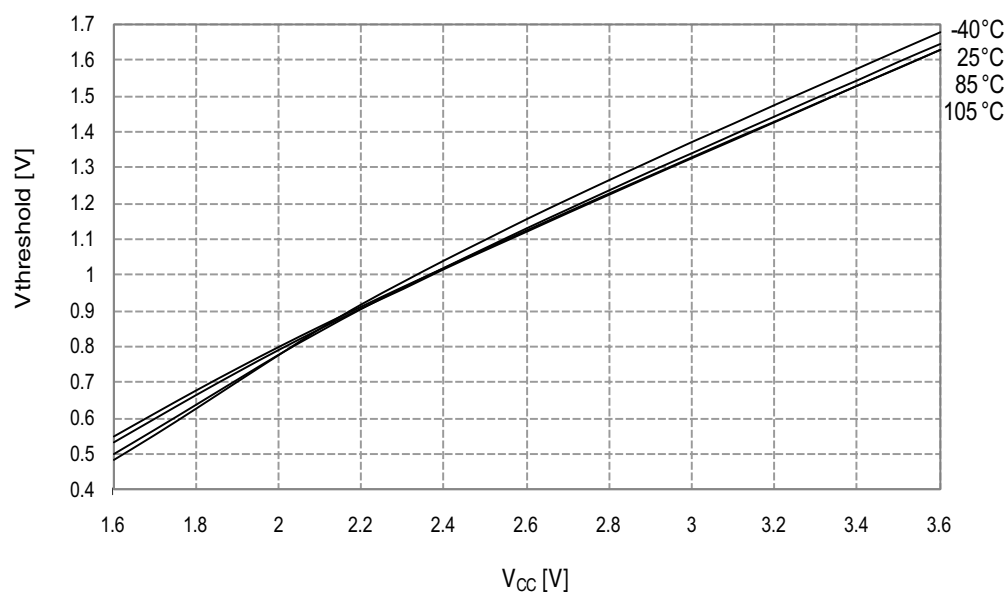
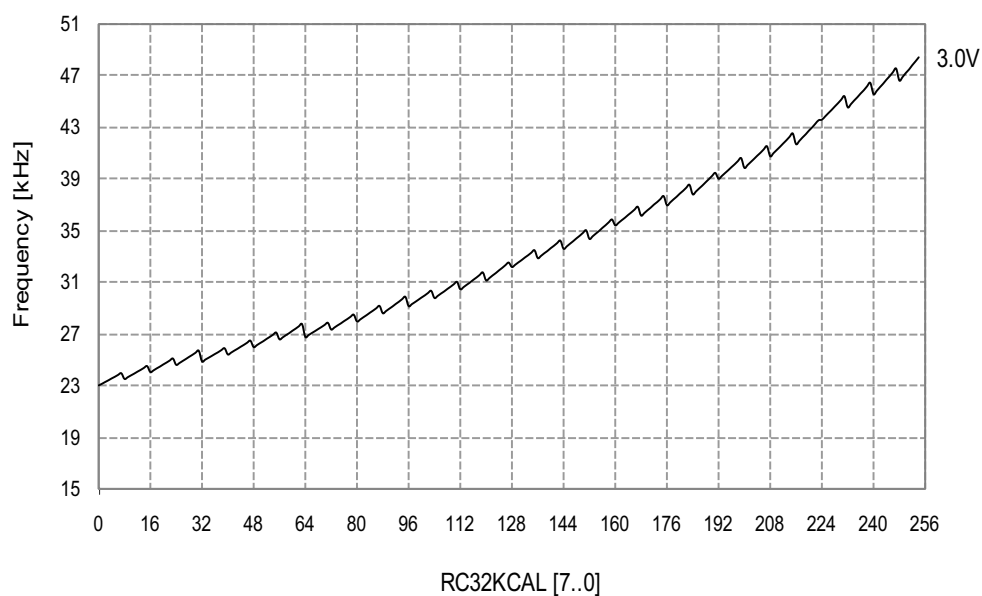


Figure 34-67. 32.768kHz Internal Oscillator Frequency vs. Calibration Value

$V_{CC} = 3.0V$, $T = 25^{\circ}C$



34.1.9.3 2MHz Internal Oscillator

Figure 34-68. 2MHz Internal Oscillator Frequency vs. Temperature

DFLL disabled

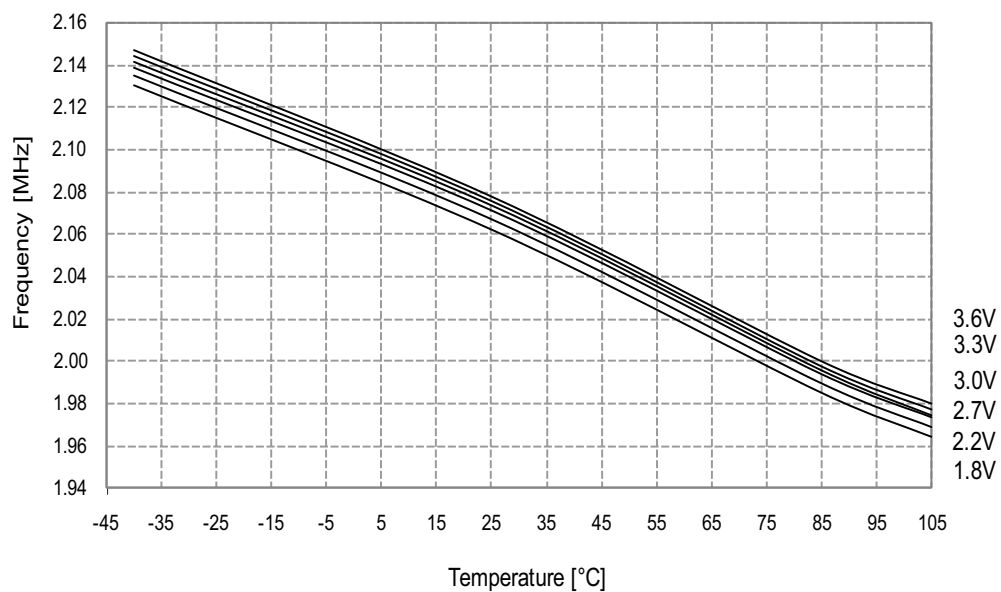


Figure 34-88. Idle Mode Supply Current vs. Frequency

$f_{SYS} = 1 - 32\text{MHz}$ external clock, $T = 25^\circ\text{C}$

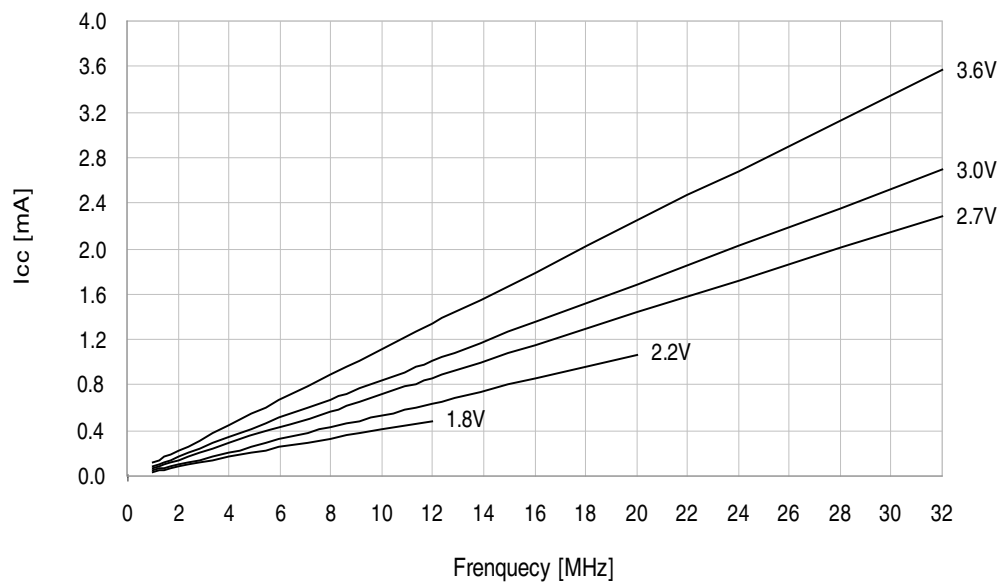


Figure 34-89. Idle Mode Supply Current vs. V_{CC}

$f_{SYS} = 32.768\text{kHz}$ internal oscillator

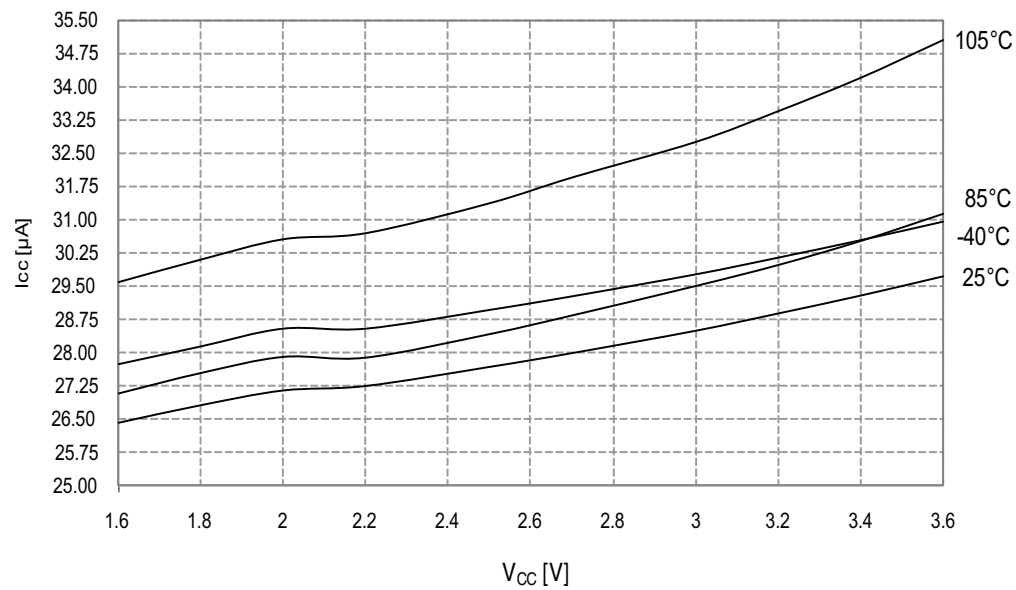


Figure 34-92. Idle Mode Supply Current vs. V_{CC}
 $f_{SYS} = 32\text{MHz}$ internal oscillator prescaled to 8MHz

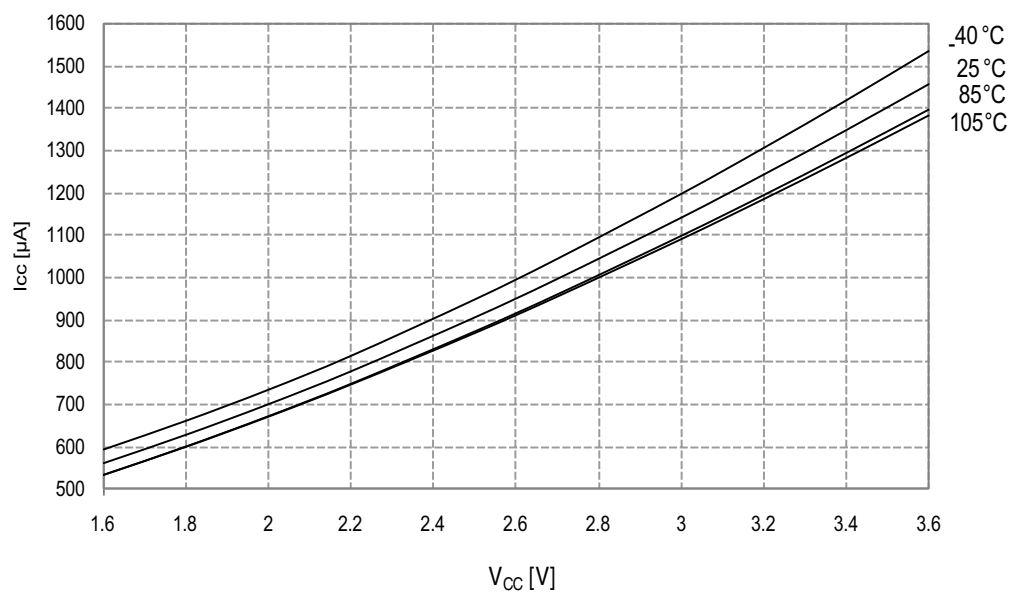
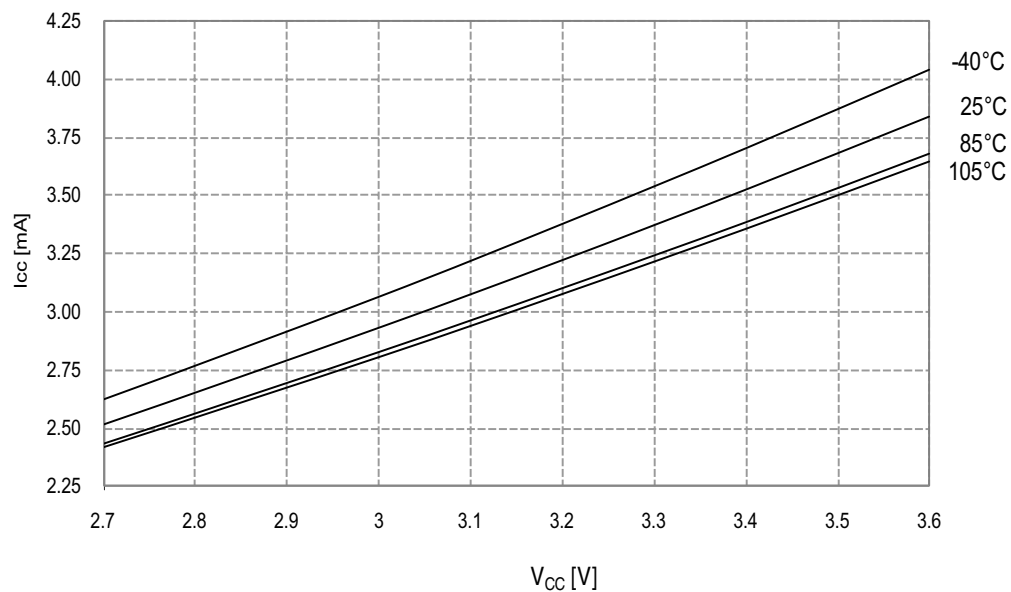


Figure 34-93. Idle Mode Current vs. V_{CC}
 $f_{SYS} = 32\text{MHz}$ internal oscillator



34.2.1.3 Power-down Mode Supply Current

Figure 34-94. Power-down Mode Supply Current vs. V_{CC}
All functions disabled

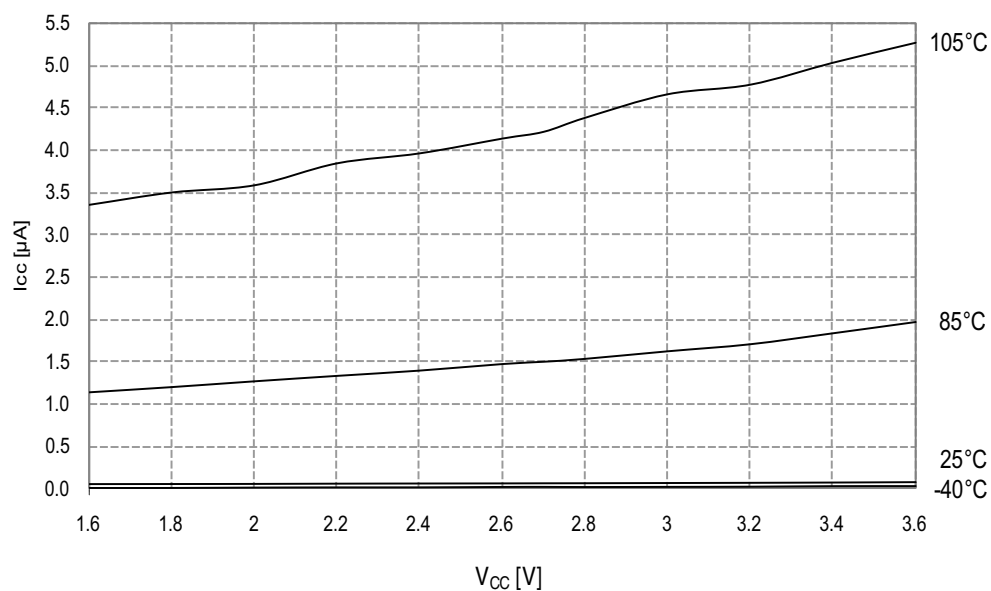


Figure 34-95. Power-down Mode Supply Current vs. V_{CC}
Watchdog and sampled BOD enabled

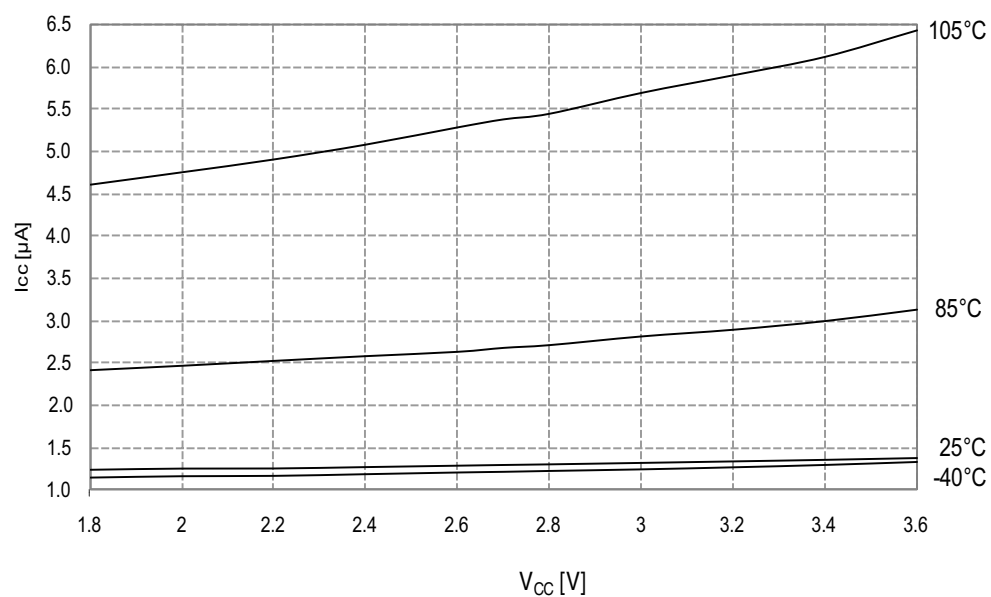


Figure 34-124. Gain Error vs. Temperature

$V_{CC} = 3.0V$, $V_{REF} = \text{external } 2.0V$

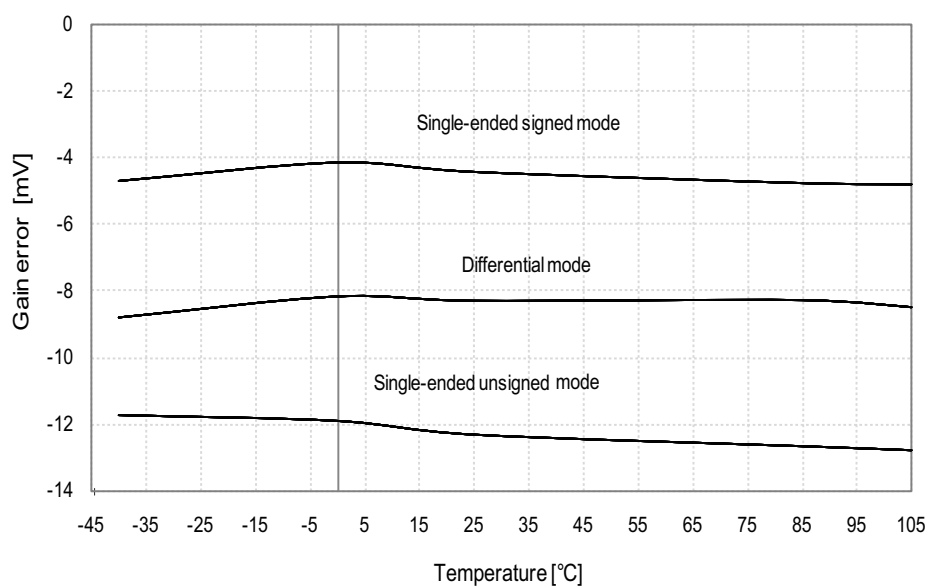
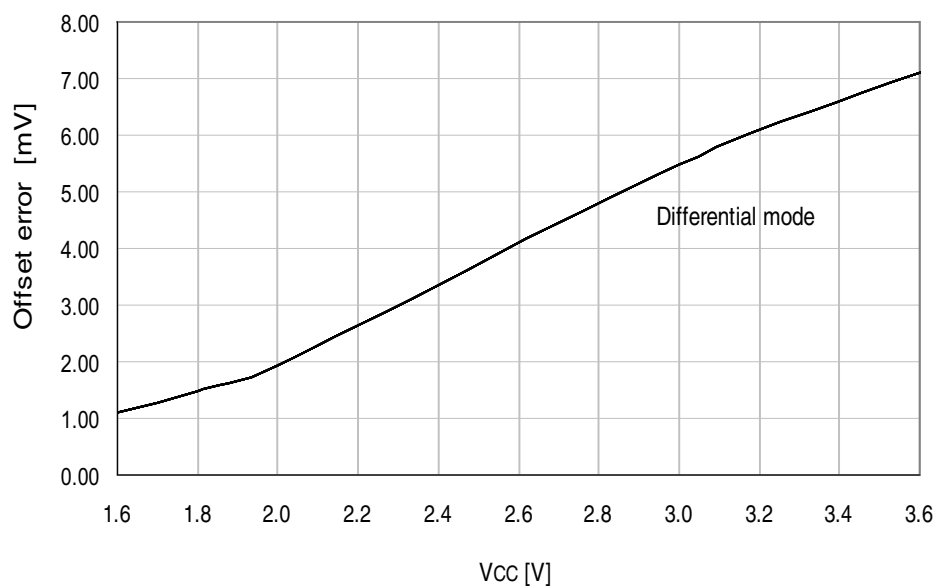


Figure 34-125. Offset Error vs. V_{CC}

$T = 25^{\circ}C$, $V_{REF} = \text{external } 1.0V$, ADC sample rate = 300ksps



34.2.4 Analog Comparator Characteristics

Figure 34-126. Analog Comparator Hysteresis vs. V_{CC}
High speed, small hysteresis

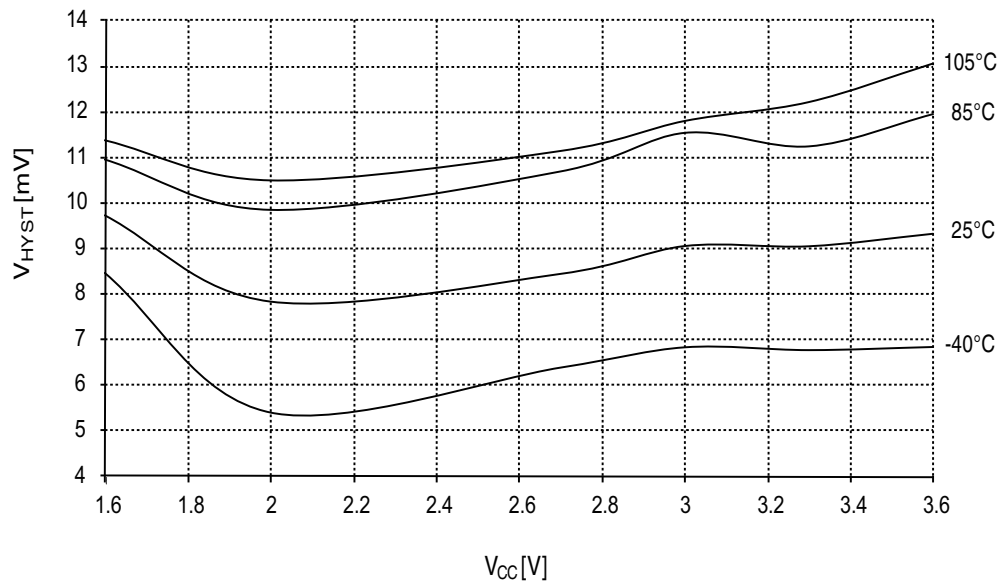


Figure 34-127. Analog Comparator Hysteresis vs. V_{CC}
High speed, large hysteresis

